



ULTRAFAST SOFT RECOVERY RECTIFIER DIODE

PRODUCT APPLICATIONS

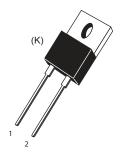
- Anti-Parallel Diode
 - -Switchmode Power Supply
 - -Inverters
- · Free Wheeling Diode
 - -Motor Controllers
 - -Converters
 - -Inverters
- · Snubber Diode
- PFC

PRODUCT FEATURES

- · Ultrafast Recovery Times
- Soft Recovery Characteristics
- · Popular TO-220 Package
- Low Forward Voltage
- · Low Leakage Current
- · Avalanche Energy Rated

PRODUCT BENEFITS

- Low Losses
- · Low Noise Switching
- · Cooler Operation
- · Higher Reliability Systems
- Increased System Power Density





- 1 Cathode
- 2 Anode
- Back of Case Cathode

MAXIMUM RATINGS

All Ratings: $T_C = 25^{\circ}C$ unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT30DQ100K(G)	UNIT	
V _R	Maximum D.C. Reverse Voltage			
V _{RRM}	Maximum Peak Repetitive Reverse Voltage	1000	Volts	
V _{RWM}	Maximum Working Peak Reverse Voltage			
I _{F(AV)}	Maximum Average Forward Current (T _C = 102°C, Duty Cycle = 0.5)	30		
I _{F(RMS)}	RMS Forward Current (Square wave, 50% duty)	43	Amps	
I _{FSM}	Non-Repetitive Forward Surge Current (T _J = 45°C, 8.3ms)	150		
E _{AVL}	Avalanche Energy (1A, 40mH)	20	mJ	
T _J ,T _{STG}	Operating and StorageTemperature Range	-55 to 175)	
T _L	Lead Temperature for 10 Sec.	300	- °C	

STATIC ELECTRICAL CHARACTERISTICS

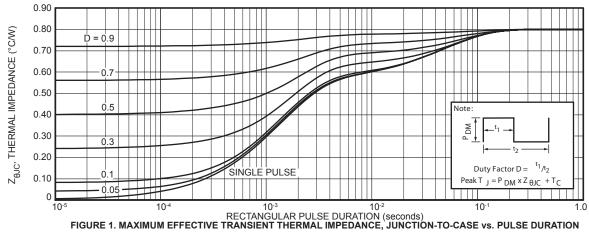
Symbol	Characteristic / Test Conditions		MIN	TYP	MAX	UNIT
V _F	Forward Voltage	I _F = 30A		2.5	3.0	Volts
		I _F = 60A		3.06		
		I _F = 30A, T _J = 125°C		1.92		
I _{RM}	Maximum Reverse Leakage Current	V _R = 1000V			100	μA
		V _R = 1000V, T _J = 125°C			500	
C _T	Junction Capacitance, V _R = 200V			26		pF

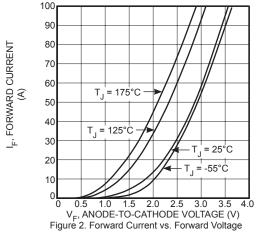
Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
t _{rr}	Reverse Recovery Time $I_F = 1A$, $di_F/dt = -100A/\mu s$, $V_R = 30V$, $T_J = 25$ °C		-	24		ns
t _{rr}	Reverse Recovery Time	$I_F = 30A$, $di_F/dt = -200A/\mu s$ $V_R = 667V$, $T_C = 25^{\circ}C$	-	295		115
Q _{rr}	Reverse Recovery Charge		-	440		nC
I _{RRM}	Maximum Reverse Recovery Current		-	4	-	Amps
t _{rr}	Reverse Recovery Time	$I_F = 30A$, $di_F/dt = -200A/\mu s$ $V_R = 667V$, $T_C = 125°C$	-	330		ns
Q _{rr}	Reverse Recovery Charge		ı	1550		nC
I _{RRM}	Maximum Reverse Recovery Current		-	8	ı	Amps
t _{rr}	Reverse Recovery Time	$I_F = 30A$, $di_F/dt = -1000A/\mu s$ $V_R = 667V$, $T_C = 125°C$	-	150		ns
Q _{rr}	Reverse Recovery Charge		-	2250		nC
I _{RRM}	Maximum Reverse Recovery Current		-	25		Amps

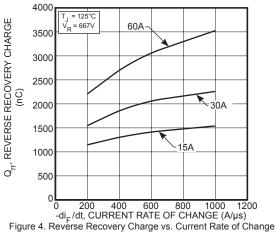
THERMAL AND MECHANICAL CHARACTERISTICS

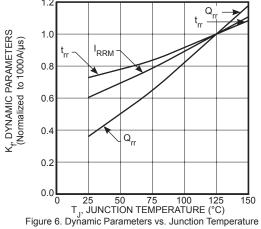
Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance			.80	°C/W
W _T	Package Weight		0.07		OZ
			1.9		g
Torque	Maximum Mounting Torque			10	lb•in
				1.1	N•m

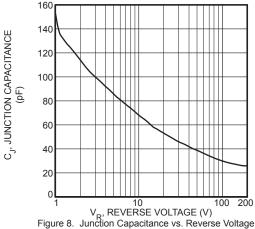
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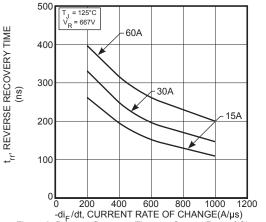
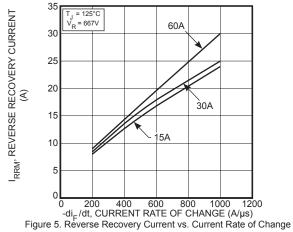


Figure 3. Reverse Recovery Time vs. Current Rate of Change



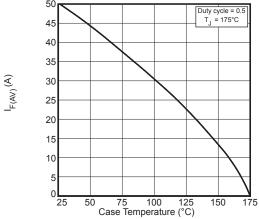


Figure 7. Maximum Average Forward Current vs. CaseTemperature

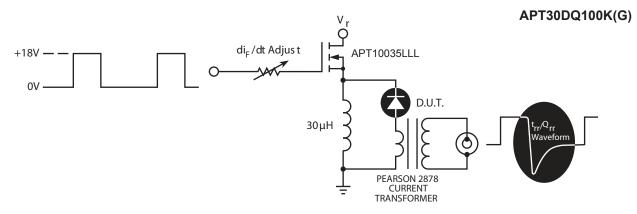


Figure 9. Diode Test Circuit

- 1 I_F Forward Conduction Current
- 2 di₋/dt Rate of Diode Current Change Through Zero Crossing.
- 3 I_{RRM} Maximum Reverse Recovery Current
- $\mathbf{4}$ \mathbf{t}_{rr} Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through \mathbf{I}_{RRM} and 0.25, \mathbf{I}_{RRM} passes through zero.
- $\mathbf{5}$ Q_{rr} Area Under the Curve Defined by I_{RRM} and t_{RR} .

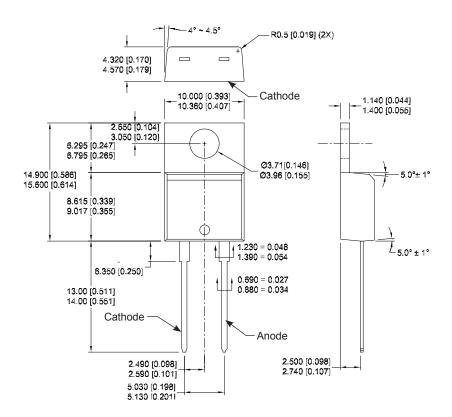
Zero

5
0.25 I_{RRM}

ugh zero.

Figure 10. Diode Reverse Recovery Waveform Definition

TO-220 (K) Package Outline e3 100% Sn



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